



20MHz, Second-Order, Isolated Delta-Sigma Modulator for Current-Shunt Measurement

Check for Samples: AMC1204, AMC1204B

FEATURES

- ±250mV Input Voltage Range Optimized for Shunt Resistors
- Certified Digital Isolation:
 - CSA, IEC60747-5-2, and UL1577 Approved
 - Isolation Voltage: 4250V_{PEAK} (AMC1204B)
 - Working Voltage: 1200V_{PEAK}
 - Transient Immunity: 15kV/µs
- Long Isolation Barrier Lifetime (see Application Report SLLA197)
- High Electromagnetic Field Immunity (see Application Note SLLA181A)
- Outstanding AC Performance:
 - SNR: 84dB (min)
 - THD: -80dB (max)
- Excellent DC Precision:
 - INL: ±8LSB (max)
 - Gain Error: ±2% (max)
- External Clock Input for Easier Synchronization
- Fully Specified Over the Extended Industrial Temperature Range

APPLICATIONS

- Shunt Resistor Based Current Sensing in:
 - Motor Control
 - Green Energy
 - Inverter Applications
 - Uninterruptible Power Supplies

DESCRIPTION

The AMC1204 and AMC1204B are 1-bit digital output, isolated delta-sigma ($\Delta\Sigma$) modulators that can be clocked at up to 20MHz. The digital isolation of the modulator output is provided by a silicon dioxide (SiO₂) barrier that is highly resistant to magnetic interference. This barrier has been certified to provide basic galvanic isolation of up to 4000V_{PEAK} (AMC1204) and 4250V_{PEAK} (AMC1204B) according to UL1577, IEC60747-5-2, and CSA standards or specifications.

The AMC1204 and AMC1204B provide a single-chip solution for measuring the small signal of a shunt resistor across an isolated barrier. These types of resistors are typically used to sense currents in motor control inverters, green energy generation systems, and other industrial applications. The AMC1204 and AMC1204B differential inputs easily connect to the shunt resistor or other low-level signal sources. An internal reference eliminates the need for external components. When used with an appropriate external digital filter, an effective number of bits (ENOB) of 14 is achieved at a data rate of 78kSPS.

A 5V analog supply (AVDD) is used by the modulator while the isolated digital interface operates from a 3V, 3.3V, or 5V supply (DVDD). The AMC1204 and AMC1204B are available in SO-16 (DW) packages and are specified from -40° C to $+105^{\circ}$ C.



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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

PACKAGE/ORDERING INFORMATION

For the most current package and ordering information see the Package Option Addendum at the end of this document, or visit the device product folder on www.ti.com.

		17				
PART NUMBER	MODULATOR CLOCK (MHz)	DIGITAL SUPPLY	CLOCK SOURCE	INL (LSB)	GAIN ERROR (%)	THD (dB)
AMC1203	10	5V	Internal	±9	±2	-84.5
AMC1203B	10	5V	Internal	±6	±1	-88
AMC1204	20	3V, 3.3V, or 5V	External	±8	±2	-80
AMC1204B	20	3V, 3.3V, or 5V	External	±8	<u>+2</u>	-80

FAMILY OVERVIEW

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Over the operating ambient temperature range, unless otherwise noted.

		AMC1204,		
	PARAMETER	MIN	MAX	UNIT
Supply voltage, AVDD to AGND or DVDD to DGND		-0.3	+6	V
Analog input voltage at VINP, VIN	IN	AGND – 0.5	AVDD + 0.5	V
Digital input voltage at CLKIN		DGND - 0.3	DVDD + 0.3	V
Input current to any pin except su	ipply pins	-10	+10	mA
Maximum virtual junction tempera		+150	°C	
Operating ambient temperature ra	ange, T _{OA}	-40	+125	°C
	Human body model (HBM) JEDEC standard 22, test method A114-C.01	-3000	+3000	V
Electrostatic discharge (ESD), all pins	Charged device model (CDM) JEDEC standard 22, test method C101	-1500	+1500	V
	Machine model (MM) JEDEC standard 22, test method A115A	-200	+200	V

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under the Electrical Characteristics is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.

THERMAL INFORMATION

	43	AMC1204, AMC1204B	
	THERMAL METRIC ⁽¹⁾	DW	UNITS
		16 PINS	
θ_{JA}	Junction-to-ambient thermal resistance	78.5	
θ _{JCtop}	Junction-to-case (top) thermal resistance	41.3	
θ_{JB}	Junction-to-board thermal resistance	50.2	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	11.5	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	41.2	
θ _{JCbot}	Junction-to-case (bottom) thermal resistance	n/a	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.



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REGULATORY INFORMATION

VDE/IEC	CSA	UL
Certified according to IEC 60747-5-2	Approved under CSA component acceptance notice	Recognized under 1577 component recognition program
File number: 40016131	File number: 2350550	File number: E181974

IEC SAFETY LIMITING VALUES

Safety limiting intends to prevent potential damage to the isolation barrier upon failure of input or output (I/O) circuitry. A failure of the I/O circuitry can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier, potentially leading to secondary system failures.

The safety-limiting constraint is the operating virtual junction temperature range specified in the Absolute Maximum Ratings table. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determine the junction temperature. The assumed junction-to-air thermal resistance in the Thermal Information table is that of a device installed in the JESD51-3, *Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages* and is conservative. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

	PARAMETER TEST CONDITIONS		MIN	TYP	MAX	UNIT
I _S	Safety input, output, or supply current	$\theta_{JA} = +78.5^{\circ}C/W, V_{I} = 5.5V, T_{J} = +150^{\circ}C, T_{A} = +25^{\circ}C$			10	mA
T_{C}	Maximum case temperature				+150	°C

IEC 61000-4-5 RATINGS

PARAMETER		TEST CONDITIONS	VALUE	UNIT
V _{IOSM}	Surge immunity	1.2/50µs voltage surge and 8/20µs current surge	±6000	V

IEC 60664-1 RATINGS

PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic isolation group	Material group	II
	Rated mains voltage ≤ 150V _{RMS}	I-IV
	Rated mains voltage < 300V _{RMS}	I-IV
Installation classification	Rated mains voltage < 400V _{RMS}	I-III
	Rated mains voltage < 600V _{RMS}	1-111

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ISOLATION CHARACTERISTICS

	PARAMETER	TEST CONDITIONS	AMC1204	AMC1204B	UNIT
VIORM	Maximum working insulation voltage per IEC		1200	1200	V _{PEAK}
V _{PD(t)}	Partial discharge test voltage per IEC	t = 1s (100% production test), partial discharge < 5pC	2250	2250	V _{PEAK}
V _{IOTM}	Transient overvoltage	t = 60s (qualification test)	4000	4250	V _{PEAK}
		t = 1s (100% production test)	4800	5100	V _{PEAK}
R _S	Isolation resistance	V_{IO} = 500V at T _S	> 10 ⁹	> 10 ⁹	Ω
PD	Pollution degree		2	2	Degrees

ISOLATOR CHARACTERISTICS⁽¹⁾

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (clearance)	Shortest terminal to terminal distance through air	7.9			mm
L(I02)	Minimum external tracking (creepage)	Shortest terminal to terminal distance across the package surface	7.9			mm
СТІ	Tracking resistance (comparative tracking index)	DIN IEC 60112/VDE 0303 part 1	> 400			V
	Minimum internal gap (internal clearance)	Distance through the insulation	0.014			mm
R _{IO}	Isolation resistance	Input to output, $V_{IO} = 500V$, all pins on each side of the barrier tied together to create a two-terminal device, $T_A < +85^{\circ}C$		> 10 ¹²		Ω
		Input to output, $V_{IO} = 500V$, +100°C ≤ $T_A < T_A$ max		> 10 ¹¹		Ω
CIO	Barrier capacitance input to output	$V_{I} = 0.8V_{PP}$ at 1MHz		1.2		pF
Cl	Input capacitance to ground	$V_{I} = 0.8V_{PP}$ at 1MHz		3		pF

(1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of a specific application. Care should be taken to maintain the creepage and clearance distance of the board design to ensure that the mounting pads of the isolator on the printed circuit board (PCB) do not reduce this distance. Creepage and clearance on a PCB become equal according to the measurement techniques shown in the *Isolation Glossary* section. Techniques such as inserting grooves and/or ribs on the PCB are used to help increase these specifications.

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ELECTRICAL CHARACTERISTICS

All minimum/maximum specifications at $T_A = -40^{\circ}$ C to +105°C, AVDD = 4.5V to 5.5V, DVDD = 2.7V to 5.5V, VINP = -250mV to +250mV, VINN = 0V, and sinc³ filter with OSR = 256, unless otherwise noted. Typical values are at $T_A = +25^{\circ}$ C, AVDD = 5V, and DVDD = 3.3V.

		AMC1204, AMC1204B			
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Specified ambient temperature range		-40		+105	°C
ION					
Resolution		16			Bits
RACY					
1-4(1)	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	8	±2	8	LSB
Integral linearity error	$T_{A} = -40^{\circ}C \text{ to } +105^{\circ}C$	-16	±5	16	LSB
Differential nonlinearity		-1		1	LSB
Offset error ⁽²⁾		-1	±0.1	1	mV
Offset error thermal drift		-3.5	±1	3.5	µV/°C
Gain error ⁽²⁾		-2	±0.5	2	%
Gain error thermal drift			±30		ppm/°C
			79		dB
	1				
	VINP – VINN		±320		mV
		-250		250	mV
,					mV
		-100	7	AVDD	pF
					pr pF
					kΩ
Differential input resistance		10	12.5	40	
Input leakage current					μA
2	$VINP - VINN = \pm 320 \text{mV}$			50	μΑ
Common-mode transient immunity		15			kV/µs
Common-mode rejection ratio					dB
-	V _{IN} from 0V to 5V at 100kHz		114		dB
L CLOCK					
Clock period		45.5	50	200	ns
Input clock frequency		5	20	22	MHz
Duty cycle	$5MHz \le f_{CLKIN} < 20MHz$	40	50	60	%
	$20MHz \le f_{CLKIN} \le 22MHz$	45	50	55	%
RACY					
Signal to poice a distortion	$f_{IN} = 1 \text{kHz}, T_A = -40^{\circ}\text{C} \text{ to } +85^{\circ}\text{C}$	78	87		dB
Signal-to-hoise + distolation	$f_{IN} = 1$ kHz, $T_A = -40$ °C to $+105$ °C	70	87		dB
	$f_{IN} = 1 \text{ kHz}, T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$	84	88		dB
Signal-to-hoise ratio	$f_{IN} = 1 \text{kHz}, T_A = -40^{\circ}\text{C to } +105^{\circ}\text{C}$	83	88		dB
T (1) (1) (1) (1) (1)	$f_{IN} = 1 \text{ kHz}, T_A = -40^{\circ} \text{C to } +85^{\circ} \text{C}$		-96	-80	dB
I otal harmonic distortion	$f_{IN} = 1 \text{kHz}, T_A = -40^{\circ}\text{C to } +105^{\circ}\text{C}$		-96	-70	dB
	$f_{IN} = 1 \text{ kHz}, T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$	82	96		dB
Spurious-free dynamic range		72	96		dB
NPUTS ⁽³⁾					
		-10		10	μA
Input current	$V_{IN} = DVDD$ to DGND	-10			P
Input current	V _{IN} = DVDD to DGND	-10	5		nF
Input capacitance	V _{IN} = DVDD to DGND		5 th Schmitt-triag		pF
	V _{IN} = DVDD to DGND		th Schmitt-trigg		pF V
	Specified ambient temperature range ION Resolution RACY Integral linearity error ⁽¹⁾ Differential nonlinearity Offset error (2) Offset error thermal drift Gain error thermal drift Power-supply rejection ratio NPUTS Full-scale differential voltage input range Specified FSR Operating common-mode signal ⁽³⁾ Input capacitance to AGND Differential input resistance Input leakage current Common-mode transient immunity Common-mode rejection ratio L CLOCK Clock period Input clock frequency Duty cycle RACY Signal-to-noise + distortion Signal-to-noise ratio Total harmonic distortion Spurious-free dynamic range	PARAMETERTEST CONDITIONSSpecified ambient temperature rangeIONResolutionResolutionCACYIntegral linearity error ⁽¹⁾ $T_A = -40^{\circ}C$ to $+85^{\circ}C$ Differential nonlinearityOffset error ⁽²⁾ Offset error ⁽²⁾ Offset error ⁽²⁾ Offset error ⁽²⁾ Gain error thermal driftGain error thermal driftPower-supply rejection ratioNPUTSFull-scale differential voltage input rangeVINP – VINNSpecified FSROperating common-mode signal ⁽³⁾ Input capacitance to AGNDDifferential input resistanceDifferential input resistanceInput leakage currentCommon-mode rejection ratioVINP – VINN = ±320mVCommon-mode rejection ratioVing from OV to 5V at 0HzVing from OV to 5V at 100kHzL CLOCKClock periodInput clock frequencyDuty cycleSignal-to-noise + distortionfins 1kHz, TA = -40°C to +85°Cfins 1kHz, TA = -40°C to +85°C <td< td=""><td>ARAMETERAMC12Specified ambient temperature rangeTEST CONDITIONSMINSpecified ambient temperature range-40ONResolution16Resolution16Resolution16ACY$T_A = -40^{\circ}C$ to +85°C-8Integral linearity error⁽¹⁾$T_A = -40^{\circ}C$ to +105°C-16Offset error⁽²⁾-1-3.5Gain error⁽²⁾-2-2Gain error⁽²⁾-2-2Gain error⁽²⁾-2-2Gain error⁽²⁾-2-2Gain error⁽²⁾-250-250Optating common-mode signal⁽³⁾-160-160Input capacitance to AGNDVINP or VINN-160Differential input capacitance-160-160Differential input capacitance-160-250Common-mode transient immunity15-250Common-mode ransient immunity15-10Common-mode ransient immunity15-10Conck period45.5-50Duty cycle5MHz ≤ f_{CLKIN} < 20MHz</td>4020Hz ≤ f_{CLKIN} < 20MHz</td<>	ARAMETERAMC12Specified ambient temperature rangeTEST CONDITIONSMINSpecified ambient temperature range-40ONResolution16Resolution16Resolution16ACY $T_A = -40^{\circ}C$ to +85°C-8Integral linearity error ⁽¹⁾ $T_A = -40^{\circ}C$ to +105°C-16Offset error ⁽²⁾ -1-3.5Gain error ⁽²⁾ -2-2Gain error ⁽²⁾ -2-2Gain error ⁽²⁾ -2-2Gain error ⁽²⁾ -2-2Gain error ⁽²⁾ -250-250Optating common-mode signal ⁽³⁾ -160-160Input capacitance to AGNDVINP or VINN-160Differential input capacitance-160-160Differential input capacitance-160-250Common-mode transient immunity15-250Common-mode ransient immunity15-10Common-mode ransient immunity15-10Conck period45.5-50Duty cycle5MHz ≤ f _{CLKIN} < 20MHz	AMC1204, AMC1204BSpecified ambient temperature rangeTEST CONDITIONSMINTYPSpecified ambient temperature range-40INTasendu integral integr	$\begin{array}{ c c c c c } \mbox{PARAMETER} & \begin{tabular}{ c c c c c } \hline PARAMETER & TEST CONDITIONS & MIN & TYP & MAX \\ \hline Specified ambient temperature range & -40 & +105 \\ \hline MIN & TYP & MAX \\ \hline Specified ambient temperature range & -40 & +105 \\ \hline ON & & & & & & & & & & & & & & & & & & $

(1) Integral nonlinearity is defined as the maximum deviation from a straight line passing through the end-points of the ideal ADC transfer function expressed as number of LSBs or as a percent of the specified 500mV input range.

(2) Maximum values, including temperature drift, are ensured over the full specified temperature range.

(3) Ensured by design.



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ELECTRICAL CHARACTERISTICS (continued)

All minimum/maximum specifications at $T_A = -40^{\circ}$ C to +105°C, AVDD = 4.5V to 5.5V, DVDD = 2.7V to 5.5V, VINP = -250mV to +250mV, VINN = 0V, and sinc³ filter with OSR = 256, unless otherwise noted. Typical values are at $T_A = +25^{\circ}$ C, AVDD = 5V, and DVDD = 3.3V.

				AMC1204, AMC1204B			
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
LVCMOS	S logic family		LVCMOS				
VIH	High-level input voltage	DVDD = 2.7V to 3.6V	2		DVDD + 0.3	V	
VIL	Low-level input voltage	DVDD = 2.7V to 3.6V	-0.3		0.8	V	
DIGITAL	OUTPUTS ⁽³⁾	·					
COUT	Output capacitance			5		pF	
C _{LOAD}	Load capacitance				30	pF	
CMOS lo	ogic family			CMOS			
V _{OH}	High-level output voltage	$DVDD = 4.5V, I_{OH} = -100\mu A$	4.4			V	
V _{OL}	Low-level output voltage	DVDD = 4.5V, I _{OL} = +100µA			0.5	V	
LVCMOS	S logic family			LVCMOS			
		I _{OH} = 20μA	DVDD - 0.1			V	
V _{OH}	High-level output voltage	$I_{OH} = -4mA,$ 2.7V \leq DVDD \leq 3.6V	DVDD - 0.4			V	
		$I_{OH} = -4mA,$ 4.5V \leq DVDD \leq 5.5V	DVDD - 0.8			V	
		I _{OL} = 20μA			0.1	V	
V _{OL}	Low-level output voltage	$I_{OL} = 4mA$			0.4	V	
POWER	SUPPLY						
AVDD	High-side supply voltage		4.5	5	5.5	V	
DVDD	Controller-side supply voltage		2.7	3.3	5.5	V	
I _{AVDD}	High-side supply current	4.5V ≤ AVDD ≤ 5.5V		11	16	mA	
	Controller side supply surrent	2.7V ≤ DVDD ≤ 3.6V		2	4	mA	
I _{DVDD}	Controller-side supply current	$4.5V \le DVDD \le 5.5V$		2.8	5	mA	
P _D	Power dissipation	AVDD = 5.5V, DVDD = 3.6V		61.6	102.4	mW	



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PIN CONFIGURATION



(1) NC = no internal connection.

PIN DESCRIPTIONS

PIN NAME	PIN#	FUNCTION	DESCRIPTION
AVDD	1	Power	High-side power supply
VINP	2	Analog input	Noninverting analog input
VINN	3	Analog input	Inverting analog input
AGND	4, 8 ⁽¹⁾	Power	High-side ground
DGND	9, 16	Power	Controller-side ground
DATA	11	Digital output	Modulator data output
CLKIN	13	Digital input	Modulator clock input
DVDD	14	Power	Controller-side power supply
NC	5, 6, 7, 10, 12, 15	—	No internal connection; can be tied to any potential or left unconnected

(1) Both pins are connected internally via a low-impedance path; thus, only one of the pins must be tied to the ground plane.

TIMING INFORMATION



Figure 1. Modulator Output Timing

TIMING CHARACTERISTICS FOR Figure 1

Over recommended ranges of supply voltage and operating free-air temperature, unless otherwise noted.

	PARAMETER	MIN	TYP	MAX	UNIT
t _{CLK}	CLKIN clock period	45.5	50	200	ns
t _{HIGH}	CLKIN clock high time	20	25	120	ns
t _{LOW}	CLKIN clock low time	20	25	120	ns
t _D	Delayed falling edge of CLKIN to DATA valid	2		15	ns



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TYPICAL CHARACTERISTICS

At AVDD = 5V, DVDD = 3.3V, VINP = -250mV to +250mV, VINN = 0V, and sinc³ filter with OSR = 256, unless otherwise noted.



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At AVDD = 5V, DVDD = 3.3V, VINP = -250mV to +250mV, VINN = 0V, and sinc³ filter with OSR = 256, unless otherwise noted.



TEXAS INSTRUMENTS

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Figure 19.

Figure 18.



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TYPICAL CHARACTERISTICS (continued)

At AVDD = 5V, DVDD = 3.3V, VINP = -250mV to +250mV, VINN = 0V, and sinc³ filter with OSR = 256, unless otherwise noted.



EXAS **NSTRUMENTS**

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At AVDD = 5V, DVDD = 3.3V, VINP = -250mV to +250mV, VINN = 0V, and sinc³ filter with OSR = 256, unless otherwise noted.





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TYPICAL CHARACTERISTICS (continued)

At AVDD = 5V, DVDD = 3.3V, VINP = -250mV to +250mV, VINN = 0V, and sinc³ filter with OSR = 256, unless otherwise noted.





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GENERAL DESCRIPTION

The AMC1204 and AMC1204B are single-channel, second-order, delta-sigma ($\Delta\Sigma$) modulators designed for medium- to high-resolution analog-to-digital conversions. The isolated output of the converter (DATA) provides a stream of digital ones and zeros. The time average of this serial output is proportional to the analog input voltage.

Figure 41 shows a detailed block diagram of the AMC1204 and AMC1204B. The analog input range is tailored to directly accommodate a voltage drop across a shunt resistor used for current sensing. The SiO₂-based capacitive isolation barrier supports a high level of magnetic field immunity as described in the application report *ISO72x Digital Isolator Magnetic-Field Immunity* (SLLA181A, available for download at www.ti.com). The external clock input simplifies the synchronization of multiple current sense channels on system level. The extended frequency range of up to 20MHz supports higher performance levels compared to the other solutions available on the market.



Figure 41. Detailed Block Diagram

THEORY OF OPERATION

TEXAS INSTRUMENTS

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The differential analog input of the AMC1204 and AMC1204B are implemented with a switched-capacitor circuit. This switched-capacitor circuit implements a second-order modulator stage that digitizes the input signal into a 1bit output stream. The externally-provided clock source at the CLKIN pin is used by the capacitor circuit and the modulator and should be in the range of 5MHz to 22MHz. The analog input signal is continuously sampled by the modulator and compared to an internal voltage reference. A digital stream, accurately representing the analog input voltage over time, appears at the output of the converter at the DATA pin.

ANALOG INPUT

The AMC1204 and AMC1204B measure the differential input signal $V_{IN} = (VINP - VINN)$ against the internal reference of 2.5V using internal capacitors that are continuously charged and discharged. Figure 42 shows the simplified schematic of the ADC input circuitry; the right side of Figure 42 illustrates the input circuitry with the capacitors and switches replaced by an equivalent circuit.

In Figure 42, the S₁ switches close during the input sampling phase. With the S₁ switches closed, C_{DIFF} charges to the voltage difference across VINP and VINN. For the discharge phase, both S₁ switches open first and then both S₂ switches close. C_{DIFF} discharges approximately to AGND + 0.8V during this phase. This two-phase sample/discharge cycle repeats with a period of $t_{CLKIN} = 1/f_{CLKIN}$ is the operating frequency of the modulator. The capacitors C_{IP} and C_{IN} are of parasitic nature and caused by bonding wires and the internal ESD protection structure.



Figure 42. Equivalent Analog Input Circuit

The input impedance becomes a consideration in designs with high input signal source impedance. This high impedance may cause degradation in gain, linearity, and THD. The importance of this effect, however, depends on the desired system performance. This input stage provides the mechanism to achieve low system noise, high common-mode rejection (105dB), and excellent power-supply rejection.

There are two restrictions on the analog input signals VINP and VINN. First, if the input voltage exceeds the range AGND - 0.5V to AVDD + 0.3V, the input current must be limited to 10mA because the input protection diodes on the front end of the converter begin to turn on. In addition, the linearity and the noise performance of the device are ensured only when the differential analog input voltage remains within ±250mV.



AMC1204

MODULATOR

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The modulator topology of the AMC1204 and AMC1204B is fundamentally a second-order, switched-capacitor, $\Delta\Sigma$ modulator, such as the one conceptualized in Figure 43. The analog input voltage (X_(t)) and the output of the 1-bit digital-to-analog converter (DAC) are differentiated, providing an analog voltage (X₂) at the input of the first integrator or modulator stage. The output of the first integrator is further differentiated with the DAC output; the resulting voltage (X₃) feeds the input of the second integrator stage. When the value of the integrated signal (X₄) at the output of the second stage equals the comparator reference voltage, the output of the comparator switches from high to low, or vice versa, depending on its previous state. In this case, the 1-bit DAC responds on the next clock pulse by changing its analog output voltage (X₆), causing the integrators to progress in the opposite direction, while forcing the value of the integrator output to track the average of the input.



Figure 43. Block Diagram of a Second-Order Modulator

The modulator shifts the quantization noise to high frequencies, as shown in Figure 44; therefore, a low-pass digital filter should be used at the output of the device to increase the overall performance. This filter is also used to convert from the 1-bit data stream at a high sampling rate into a higher-bit data word at a lower rate (decimation). A digital signal processor (DSP), microcontroller (μ C), or field programmable gate array (FPGA) can be used to implement the filter. Another option is to use a suitable application-specific device such as the AMC1210, a four-channel digital sinc-filter.



Figure 44. Quantization Noise Shaping



DIGITAL OUTPUT

A differential input signal of 0V ideally produces a stream of ones and zeros that are high 50% of the time and low 50% of the time. A differential input of +250mV produces a stream of ones and zeros that are high 78.1% of the time. A differential input of -250mV produces a stream of ones and zeros that are high 21.9% of the time. This is also the specified linear input range of the modulator with the performance as specified in this data sheet. The range between 250mV and 320mV (absolute values) is the non-linear range of the modulator. The output of the modulator clips with a stream of only zeros with an input less than or equal to -320mV or with a stream of only ones with an input greater than or equal to 320mV. The input voltage versus the output modulator signal is shown in Figure 45.

The system clock of the AMC1204 and AMC1204B is typically 20MHz and is provided externally at the CLKIN pin. The data are synchronously provided at 20MHz at the DATA output pin. The data are changing at the falling edge of CLKIN; for more details see the Timing Information section.



Figure 45. Analog Input versus AMC1204 Modulator Output

FILTER USAGE

The modulator generates a bit stream that is processed by a digital filter to obtain a digital word similar to a conversion result of a conventional analog-to-digital converter (ADC). A very simple filter, built with minimal effort and hardware, is a sinc³-type filter, as shown in Equation 1:

$$H(z) = \left(\frac{1 - z^{-OSR}}{1 - z^{-1}}\right)^{3}$$
(1)

This filter provides the best output performance at the lowest hardware size (count of digital gates). For an oversampling rate (OSR) in the range of 16 to 256, this filter is a good choice. All the characterization in this document is also done with a sinc³ filter with OSR = 256 and an output word width of 16 bits.



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In a sinc³ filter response (shown in Figure 46 and Figure 47), the location of the first notch occurs at the frequency of output data rate $f_{DATA} = f_{CLK}/OSR$. The –3dB point is located at half the Nyquist frequency or $f_{DATA}/4$. For some applications, it may be necessary to use another filter type with different frequency response. Performance can be improved, for example, by using a cascaded filter structure. The first decimation stage could be built of a sinc³ filter with a low OSR and the second stage using a high-order filter.







The effective number of bits (ENOB) is often used to compare the performance of ADCs and $\Delta\Sigma$ modulators. Figure 48 illustrates the ENOB of the AMC1204 and AMC1204B with different oversampling ratios. In this data sheet, this number is calculated from SNR using Equation 2:

$$SNR = 1.76dB + 6.02dB \times ENOB$$

(2)

In motor control applications, a very fast response time for overcurrent detection is required. The time for fully settling the filter depends on its order; that is, a sinc³ filter requires three data clocks for full settling (with $f_{DATA} = f_{CLK}/OSR$). Therefore, for overcurrent protection, filter types other than sinc³ might be a better choice; an alternative is the sinc² filter. Figure 49 compares the settling times of different filter orders with sincfast being a modified sinc² filter with behavior as shown in Equation 3.

$$H(z) = \begin{pmatrix} 1 - z^{-0SR} \\ 1 - z^{-1} \end{pmatrix}^{c} (1 + z^{-2OSR})$$
(3)







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An example code for an implementation of a sinc³ filter in an FPGA follows. For more information, see the application note *Combining ADS1202 with FPGA Digital Filter for Current Measurement in Motor Control Applications (SBAA094)*, available for download at www.ti.com.

```
library IEEE;
use IEEE.std_logic_1164.all;
use IEEE.std_logic_unsigned.all;
entity FLT is
 port(RESN, MOUT, MCLK, CNR : in std_logic;
      CN5 : out std_logic_vector(23 downto 0));
end FLT;
architecture RTL of FLT is
  signal DN0, DN1, DN3, DN5 : std_logic_vector(23 downto 0);
  signal CN1, CN2, CN3, CN4 : std_logic_vector(23 downto 0);
  signal DELTA1 : std_logic_vector(23 downto 0);
begin
process(MCLK, RESn)
 begin
    if RESn = '0' then
     DELTA1 <= (others => '0');
    elsif MCLK'event and MCLK = '1' then
     if MOUT = '1' then
        DELTA1 <= DELTA1 + 1;
      end if;
    end if;
  end process;
process(RESN, MCLK)
  begin
    if RESN = '0' then
      CN1 <= (others => '0');
     CN2 <= (others => '0');
    elsif MCLK'event and MCLK = '1' then
      CN1 <= CN1 + DELTA1;
     CN2 \leq CN2 + CN1;
    end if;
  end process;
process(RESN, CNR)
 begin
    if RESN = '0' then
     DN0 <= (others => '0');
     DN1 <= (others => '0');
      DN3 <= (others => '0');
     DN5 <= (others => '0');
    elsif CNR'event and CNR = '1' then
      DNO <= CN2;
      DN1 \leq DN0;
     DN3 <= CN3;
     DN5 <= CN4;
    end if;
  end process;
CN3 <= DN0 - DN1;
CN4 <= CN3 - DN3;
CN5 <= CN4 - DN5;
end RTL;
```



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APPLICATION INFORMATION

A typical operation of the AMC1204 and AMC1204B in a motor control application is shown in Figure 50. Measurement of the motor phase current is done via the shunt resistor R_{SHUNT} (in this case, a two-terminal shunt). For better performance, the differential signal is filtered using RC filters (components R_2 , R_3 , and C_2). Optionally, C_3 and C_4 can be used to reduce charge dumping from the inputs. In this case, care should be taken when choosing the quality of these capacitors—mismatch in values of these capacitors leads to a common-mode error at the input of the modulator.

The high-side power supply (AVDD) for the AMC1204 and AMC1204B is derived from the power supply of the upper gate driver. For lowest cost, a zener diode can be used to limit the voltage to 5V ±10%. A decoupling capacitor of 0.1 μ F is recommended for filtering this power-supply path. This capacitor (C₁ in Figure 50) should be placed as close as possible to the AVDD pin for best performance. If better filtering is required, an additional 1 μ F to 10 μ F capacitor can be used. The floating ground reference AGND is derived from the end of the shunt resistor, which is connected to the negative input (VINN) of the AMC1204 and AMC1204B. If a four-terminal shunt is used, the inputs of AMC1204 and AMC1204B are connected to the inner leads, while AGND is connected to one of the outer leads of the shunt. Both digital signals, CLKIN and DATA, can be directly connected to a digital filter (for example, the AMC1210); see Figure 51.



(1) Place C_1 close to the AMC1204 and AMC1204B.

Figure 50. Typical Application Diagram



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Figure 51 shows an example of two AMC1204 and AMC1204B devices and one ADS1209 (a dual-channel, 10MHz, non-isolated modulator) connected to an AMC1210, building the entire analog front-end of a resolver-based motor control application.

For detailed information on the ADS1209 and AMC1210, visit the respective device product folders at www.ti.com.



Figure 51. Example of a Resolver-Based Motor Control Analog Front-End



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A layout recommendation showing the critical placement of the decoupling capacitor on the high-side and placement of the other components required by the AMC1204 and AMC1204B is presented in Figure 52.



Figure 52. Recommended Layout



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ISOLATION GLOSSARY

Creepage Distance: The shortest path between two conductive input to output leads measured along the surface of the insulation. The shortest distance path is found around the end of the package body.



Clearance: The shortest distance between two conductive input to output leads measured through air (line of sight).



Input-to-Output Barrier Capacitance: The total capacitance between all input terminals connected together, and all output terminals connected together.

Input-to-Output Barrier Resistance: The total resistance between all input terminals connected together, and all output terminals connected together.

Primary Circuit: An internal circuit directly connected to an external supply mains or other equivalent source that supplies the primary circuit electric power.

Secondary Circuit: A circuit with no direct connection to primary power that derives its power from a separate isolated source.

Comparative Tracking Index (CTI): CTI is an index used for electrical insulating materials. It is defined as the numerical value of the voltage that causes failure by tracking during standard testing. Tracking is the process that produces a partially conducting path of localized deterioration on or through the surface of an insulating material as a result of the action of electric discharges on or close to an insulation surface. The higher CTI value of the insulating material, the smaller the minimum creepage distance.

Generally, insulation breakdown occurs either through the material, over its surface, or both. Surface failure may arise from flashover or from the progressive degradation of the insulation surface by small localized sparks. Such sparks are the result of the breaking of a surface film of conducting contaminant on the insulation. The resulting break in the leakage current produces an overvoltage at the site of the discontinuity, and an electric spark is generated. These sparks often cause carbonization on insulation material and lead to a carbon track between points of different potential. This process is known as tracking.

Insulation:

Operational insulation—Insulation needed for the correct operation of the equipment.

Basic insulation—Insulation to provide basic protection against electric shock.

Supplementary insulation—Independent insulation applied in addition to basic insulation in order to ensure protection against electric shock in the event of a failure of the basic insulation.

Double insulation—Insulation comprising both basic and supplementary insulation.

Reinforced insulation—A single insulation system that provides a degree of protection against electric shock equivalent to double insulation.



Pollution Degree:

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Pollution Degree 1—No pollution, or only dry, nonconductive pollution occurs. The pollution has no influence on device performance.

Pollution Degree 2—Normally, only nonconductive pollution occurs. However, a temporary conductivity caused by condensation is to be expected.

Pollution Degree 3—Conductive pollution, or dry nonconductive pollution that becomes conductive because of condensation, occurs. Condensation is to be expected.

Pollution Degree 4—Continuous conductivity occurs as a result of conductive dust, rain, or other wet conditions.

Installation Category:

Overvoltage Category—This section is directed at insulation coordination by identifying the transient overvoltages that may occur, and by assigning four different levels as indicated in IEC 60664.

- 1. Signal Level: Special equipment or parts of equipment.
- 2. Local Level: Portable equipment, etc.
- 3. Distribution Level: Fixed installation.
- 4. Primary Supply Level: Overhead lines, cable systems.

Each category should be subject to smaller transients than the previous category.

Page

REVISION HISTORY

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Cł	nanges from Revision B (August 2011) to Revision C Pa	age
•	Added AMC1204B to document	1
•	Changed Certified digital isolation, isolation voltage Feature bullet	1
•	Changed Description section to include AMC1204B	
•	Added AMC1204B row to Family Overview table	2
•	Added AMC1204B values to Isolation Characteristics table	
•	Changed AMC1204 V _{IOTM} t = 1s value in Isolation Characteristics table	. 4
•	Changed CTI minimum specification in Isolator Characteristics table	. 4
•	Changed footnote 1 in Electrical Characteristics table	5
•	Changed Analog Inputs, V _{CM} parameter minimum specification and unit in Electrical Characteristics table	. 5
•	Changed Digital Output, C _{OUT} and C _{LOAD} parameters unit specifications in Electrical Characteristics table	. 6
•	Changed package name from TSSOP to SO	
•	Updated Figure 50	21
•	Updated Figure 51	22
•	Updated Figure 52	23

Changes from Revision A (April 2011) to Revision B Changed value of V_{IOSM} parameter in IEC 61000-4-5 Ratings table 3

26 Submit Documentation Feedback

24-Jan-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
AMC1204BDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	1204B	Samples
AMC1204BDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	1204B	Samples
AMC1204DW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	AMC1204	Samples
AMC1204DWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	AMC1204	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ Only one of markings shown within the brackets will appear on the physical device.

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24-Jan-2013

OTHER QUALIFIED VERSIONS OF AMC1204 :

• Automotive: AMC1204-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*A	Il dimensions are nominal												
	Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
	AMC1204BDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
	AMC1204DWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1

TEXAS INSTRUMENTS

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PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
AMC1204BDWR	SOIC	DW	16	2000	367.0	367.0	38.0
AMC1204DWR	SOIC	DW	16	2000	367.0	367.0	38.0

DW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013 variation AA.



LAND PATTERN DATA



NOTES:

A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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